

ATTY DOCKET NO.  
**03500.010106.5**APPLICATION NO.  
**NOT YET ASSIGNED**

APPLICANT

**TOSHIKAZU OHNISHI ET AL.**

FILING DATE

**FILED HEREWITH**

GROUP

**2879**

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		<b>6,348,761 B1</b>	<b>2/02</b>	<b>Nomura et al.</b>	<b>313</b>	<b>495</b>	<b>6/94</b>
		<b>4,949,019</b>	<b>8/90</b>	<b>Isaka et al.</b>	<b>445</b>	<b>6</b>	
		<b>5,066,883</b>	<b>11/91</b>	<b>Yoshioka et al.</b>	<b>313</b>	<b>309</b>	
		<b>5,006,883</b>	<b>11/91</b>	<b>Yoshioka et al.</b>	<b>313</b>	<b>309</b>	
		<b>4,954,744</b>	<b>8/90</b>	<b>Suzuki et al.</b>	<b>313</b>	<b>336X</b>	
		<b>5,285,129</b>	<b>2/94</b>	<b>Takeda et al.</b>	<b>313</b>	<b>336X</b>	
		<b>5,256,936</b>	<b>12/89</b>	<b>Itoh et al.</b>	<b>313</b>	<b>309X</b>	
		<b>5,141,460</b>	<b>8/92</b>	<b>Jaskie et al.</b>	<b>313</b>	<b>309X</b>	

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
		<b>0523702A1</b>	<b>1/93</b>	<b>EPO</b>			<b>Abstract</b>
		<b>1283749A</b>	<b>12/89</b>	<b>JAPAN</b>			<b>Abstract</b>
		<b>A1309242</b>	<b>12/89</b>	<b>JAPAN</b>			<b>No</b>
		<b>536731A1</b>	<b>1/93</b>	<b>EPO</b>			
		<b>1-309242</b>	<b>12/89</b>	<b>JAPAN</b>			<b>Translation</b>
		<b>0 299 461</b>	<b>1/89</b>	<b>EPO</b>			

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	"Scanning Tunnelling Microscopic Investigations of Electroformed Planar Metal-Insulator-Metal Diodes," H. Pagnia, N. Sotnik and W. Wirth, Int. J. Electronics, Vol. 69, No. 1, 25-32 (1990)
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